

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1518SERIAL NO.
09/653,156

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

JAN 12 2001

APPLICANT Vishnu K. Agarwal

FILING DATE
August 31, 2000GROUP
2831

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
✓	AA	09/653,149		Derderian			08/31/00
✓	AB	09/652,532		Derderian			08/31/00
✓	AC						
✓	AD						
✓	AE						
✓	AF						
✓	AG						
✓	AH						
✓	AI						
✓	AJ						
✓	AK						
✓	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
✓	AM							
✓	AN							
✓	AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

✓	AP		A.W. Ott, et al., "Atomic layer controlled deposition of Al ₂ O ₃ films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pp. 128-136.				
✓	AQ						
✓	AR						

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2001U.S. DEPARTMENT OF COMMERCE
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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
✓	AA	6,180,481	01-2001	Deboer et al			
✓	AB	6,218,256	04-2001	Agarwal			
✓	AC	6,104,049	08-2000	Solayappan et al			
✓	AD	6,180,447	01-2001	Park et al			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1518		SERIAL NO. 09/653,156	
CIPR JGK AUG 19 2001 PATENT & TRADEMARK OFFICE		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Vishnu K. Agarwal			
		FILING DATE August 31, 2000		GROUP 2831				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
A	AA	6,274,428	08/2001	Wu				
B	AB	6,124,158	09/2000	Dautartas et al				
C	AC	6,144,060	11/2000	Park et al				
D	AD	5,316,982	05/1994	Taniguchi				
E	AE							
F	AF							
G	AG							
H	AH							
I	AI							
J	AJ							
K	AK							
L	AL							
FOREIGN PATENT DOCUMENTS								
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